

**Search Notes**

Application/Control No.

10/791,180

Examiner

Tse Chen

Applicant(s)/Patent under  
Reexamination

FREKER ET AL.

Art Unit

2116

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text search only see "rpt prove"		TSC